## **Graph-Constrained Group Testing**

Mahdi Cheraghchi et al. presented by Ying Xuan

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Mahdi Cheraghchi et al. presented by Ying Xuan Graph-Constrained Group Testing

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Possible Usages and Relaxations

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## Applications call for connected pools



- detection of congested links in IP networks or all-optical networks using probes.
- detection of dead nodes or links in sensor networks using testing packets.
- detection of infected individuals using human agents.

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All need the testing pools to be walks by the probe/packet/agent.

## Four Problem Variations for detecting defected vertices

Given a Undirected non-weighted graph G = (V, E) with |V| = nand at most  $d \ll n$  defected vertices; find the *d*-disjunct matrix standing for the testing pools.



- (Fixed Testing Entrances) all the probes starting from *r* designated vertices (entry), no constraint on the exit;
- (Fixed Testing Exit) all the probes stops at a designated sink node (exit), no constraint on the entrance;
- Fixed Testing Entrances and Exit;
- No constraints on Entrances and Exit

Similar for detecting detected edges.

## Necessary Constraints on the underlying graph

#### (D, c)-uniform

 $D \leq deg(v) \leq cD$  for special parameters D, c > 1 and  $\forall v \in V$ .

### $(\frac{1}{2}cn)^2$ -mixing time

The smallest integer T(n) = t such that a random walk of length t starting at  $\forall v \in V$ ends up having a distribution  $\mu'$  with

$$\|\mu' - \mu\|_{\infty} = \max_{i \in \Omega} \|\mu(i) - \mu'(i)\| < (\frac{1}{2}cn)^2$$

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## Equivalent Constraints

Specially, the graph can either be the following two kinds

- a random graph  $G(n, \frac{c^2 d \log^2 n}{n});$
- any graph with conductance

$$\Phi(G) := \min_{S \subseteq V: \sum_{v \in S} deg(v) \le |E|} \frac{E(S, \overline{S})}{\sum_{v \in S} deg(v)} = \Omega(1)$$

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if we need  $T(n) = O(\log n)$  (can be relaxed).

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## Algorithms

Construct each row of the testing matrix independently from a walk by letting each walked through vertices as 1, others as 0. The *d*-disjunct matrices with probability 1 - o(1) for different problem variations are:

- (Fixed Testing Entrances) m<sub>1</sub> × |V|: each walk starts from a designated entry vertex, having t<sub>1</sub> hops.
- (Fixed Testing Exit) m<sub>4</sub> × |V|: each walk starts from an arbitrary vertex, and ends at the designated exit vertex.
- (Fixed Testing Entrances and Exit) m<sub>3</sub> × |V|: each walk starts from a designated entry vertex, and ends at the designated exit vertex.
- (No constraints on Entrances and Exit)
  m<sub>2</sub> × |V|: each walk starts from an arbitrary vertex, having t<sub>2</sub> hops.

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| Parameter  | Value                         |
|------------|-------------------------------|
| $D_0$      | $O(c^2 dT^2(n))$              |
| $m_1, m_2$ | $O(c^4 d^2 T^2(n) \log(n/d))$ |
| $m_3$      | $O(c^8d^3T^4(n)\log(n/d))$    |
| $m_4$      | $O(c^9d^3DT^4(n)\log(n/d))$   |
| $t_1$      | $O(n/(c^3 dT(n)))$            |
| $t_2$      | $O(nD/(c^3dT(n)))$            |

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## Three probabilities

#### Definition

Consider a random walk  $W := (v_0, v_1, ..., v_t)$  of length *t* where all these vertices form a Markov chain. Define three probabilities related to W:

- $\pi_v$  the probability that W passes any single node v;
- $\pi_{v,A}$  the probability that W of length t passes node v, but none of the vertices in Awhere  $A \subseteq V$  and  $v \notin A$ .
- $\pi_{v,A}^{u}$  the probability that W with sink (exit) u passes node v, but none of the vertices in A where  $A \subseteq V$  and  $v \notin A$ .

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# Why we need (D, c)-uniform?

#### Lemma

Denote by  $\mu$  the stationary distribution of G, then for each  $v \in V$ ,  $\mu(v) \in [\frac{1}{cn}, \frac{c}{n}]$ .

#### Proof.

 $(D, c) - uniform \Rightarrow D \le deg(v) \le cD \Rightarrow nD \le 2|E| = sum_v deg(v) \le ncD$ 

property: a random walk on any graph that is not bipartite converges (finite number of steps) to a stationary distribution  $\mu(v) = \frac{\deg(v)}{2|E|}$ 

Apparently, this is loose, so D, c-uniform can be relaxed for specific topology.

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## Why we need $\delta$ -mixing time

#### Lemma

$$\pi = \Omega(\frac{t}{cnT(n)})$$

#### Proof.

Assume the random walk  $W = \{w_0, w_1, \dots, w_{t/T(n)}\}$  with  $w_i = v_{iT(n)}$  (scale to T(n)), from the definition of  $\delta$ -mixing time, where  $\delta = (\frac{1}{2}cn)^2$ , we can see

$$\begin{aligned} \Pr[w_0 \neq v, w_1 \neq v, \cdots, w_t \neq v] &\leq (1 - 1/cn + \delta)^{t/T(n)} \\ &\leq (1 - 1/2cn)^{2t/T(n)} \\ &\leq \exp(-t/(cnT(n))) \\ &\leq 1 - \Omega(t/cn(T(n))) \end{aligned}$$

If  $\mu(\mathbf{v})$  can be tightened,  $\delta$  can be enlarged, so that t could be smaller, so the matrix will have smaller row weight.

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### What do we need to lower bound $\pi_{\nu,A}$

**Idea:** we don't want the walk to enter the set A within t steps, so we can upper bound the probability of <u>each vertices being passed for more than k > 1 times</u> and being passed within the first h steps. Can we get h larger enough than t so we can avoid passing the vertices in A? Not that straightforward.

#### Lemma

There is a  $k = O(c^2 T(n))$  such that for every  $v \in V$ , the probability that W passes v more than k times is at most  $\pi_v/4$ 

#### Lemma

For any walk W, if v is not a designated entrance vertex, then the probability that W visits v within the first h steps is at most h/D.

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## Lower Bounding $\pi_{v,A}$

#### Theorem

For the first algorithm (Fixed Testing entries) with  $D_0$  and  $t_1$  mentioned above. Let  $v \in V$  and  $A \subseteq V$  be a subset of at most d vertices in G such that  $v \in A$  and  $A \cap \{v\}$  does not include any of the designated vertices  $s_1, s_2, \dots, s_r$ , then

$$\pi_{v,A} = \Omega(\frac{1}{c^4 dT^2(n)})$$

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## Proof

#### Proof.

- $\mathcal{G} := \text{event that } \underline{W \text{ hits } v \text{ no more than } k = O(c^2T(n)) \text{ times and never within } \underline{\text{the first } 2T(n) \text{ steps.}} \Rightarrow Pr[\mathcal{G}] \ge 1 2T(n)/D O(t/cnT(n));$
- B := event that <u>W</u> hits some vertex in A ⇒ π<sub>v,A</sub> ≥ Pr[¬B, v ∈ W, G];
- upperbound  $Pr[\mathcal{B}|v \in W, \mathcal{G}]$ ;
- lowerbound  $\pi_{v,A}$ .

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# upperbound $Pr[\mathcal{B}|v \in W, \mathcal{G}]$

#### Proof.

- fix i > 2T(n) and  $v_i = v$ , i.e. assume W visits v after 2T(n) steps;
- divide the walk into four parts W<sub>1</sub>, W<sub>2</sub>, W<sub>3</sub>, W<sub>4</sub> with intervals
  (0, T(n)), (T(n) + 1, i T(n) 1), (i T(n), i + T(n)), (i + T(n) + 1, t);
- bound  $\mathcal{B}$  for each node in each interval, and get loose union bound for each ivalue as  $Pr[\mathcal{B}|v_i, \mathcal{G}] \leq 1.1(\frac{6dT(n)}{D} + \frac{4dct}{n})$
- since W hits v no more than k times, consider t > 2T(n) events v<sub>i</sub> = v for i = [2T(n) + 1, t], their intersection is empty. Since v ∈ W is the union of these events, we have a union bound

$$Pr[\mathcal{B}|v \in W, \mathcal{G}] = O(c^2 T(n)(\frac{6dT(n)}{D} + \frac{4dct}{n}))$$

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## Main Theorem

#### Correctness of the first algorithm

The first algorithm returns a  $O(c^4D^2T^2(n)\log(n/d)) \times n$  d-disjunct matrix for  $D > O(c^dT^2(n))$  and  $t = O(n/(c^3dT(n)))$ .

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### Proof

- $X_i :=$  the *i*<sup>th</sup> row has 1 at column v and all 0 at |A| < d columns, so  $E[X_i] = Pr[X_i = 1] = \pi_{v,A};$
- failure probability for all  $v \in V$  and *d*-subset *A* is  $p_f \leq \sum_{v,A} (1 - \pi_{v,A})^m \leq exp(d \log \frac{n}{d}) \left(1 - \Omega(\frac{1}{c^4 dT^2(n)})\right)^m = o(1)$

## Relaxations

- (D, c)-uniform;
- δ-mixing time;
- calculation of the failure probability;

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## **Possible Usages**

- study on specific topologies instead of arbitrary graph;
- divide the graph into multiple subgraphs that satisfy the graph constraint;

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## The End

### Q & A

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